Calibrated Single Crystal Diamond Tip-Nanoindentation,/ Nanoscratching/ Lithography-b

CSCDT-NI/NS/L-b

These tips are specifically designed for high mechanical loads and scratch testing applications. By using wear-resistant diamond and a board cone angle the contact size is well characterized and stays constant during repeated mechanical measurements. These probes have demonstrated highly repeatable deep (~100nm) indentations into materials such as fused silica and are able to image the indents at high resolution in-situ using the same probe. A gold reflex coating deposited on the detector side of the cantilever to enhance the reflectance of the laser beam.

SPECIFICATIONS

short_desc	Calibrated Unique Probes with Single Crystal Diamond Tip Specially Designed for Nanoindentation, Nanoscratching, and Lithography
Categories	AFM Probes, Diamond
Tags	: Hardened/Enhanced Wear Resistance, Nanoindentation and Lithography
Quantity	5
Cantilever Length	125
Cantilever Width	30
Cantilever Thickness	4
Resonant Frequency [kHz]	500, 750, 1000
Force Constant [N/m]	100, 350, 600
Coating	Au Reflective
Cantilever Shape	Rectangular
Cantilever	Single
Tip	4 Sided Pyramid
Tip Material	Diamond